


<b>Search Notes</b>  	<b>Application/Control No.</b>  10585850	<b>Applicant(s)/Patent Under Reexamination</b>  ISHIKAWA ET AL.
	<b>Examiner</b>  SHIN-HON CHEN	<b>Art Unit</b>  2431

SEARCHED			
Class	Subclass	Date	Examiner
713	150	11/23/09	S.C.
726	3, 5	11/23/09	S.C.
709	224, 245	11/23/09	S.C.

SEARCH NOTES		
Search Notes	Date	Examiner
USPAT, PGPUB, DERWENT, JPO, EPO (BRS search)	11/23/09	S.C.

INTERFERENCE SEARCH			
Class	Subclass	Date	Examiner

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